

In the claims:

Please amend the claims as follows:

1. (Original): An apparatus for indicating real time focus in a scanning microscope, the apparatus comprising:

a detector for detecting an electrical signal from the scanning microscope;  
one or more bandpass filters for filtering the detected electrical signal, wherein the one or more bandpass filters are tuned to a desired range of frequencies; and  
one or more power indicators for detecting and displaying average power of the filtered electrical signal of a corresponding bandpass filter.

2. (Original): The apparatus of Claim 1, wherein the one or more bandpass filters comprises at least one of a low, medium, or high pass filter.

3. (Original): The apparatus of Claim 1, further comprising a focusing device for generating a focusing signal based on the detected average power and focusing the scanning microscope based on the generated focusing signal.

4. (Original): The apparatus of Claim 3, wherein the focusing device automatically performs generating and focusing.

5. (Original): The apparatus of Claim 1, wherein the scanning microscope is a confocal microscope.

6. (Currently Amended): A method for indicating real time focus in a scanning microscope, the method comprising:

detecting an electrical signal from the scanning microscope;  
filtering the detected electrical signal according to one or more frequency ranges; and  
detecting average power of the filtered electrical signal for each of the one or more frequency ranges; and  
displaying each of the detected average powers of the electrical signal.

7. (Original): The method of Claim 6, wherein filtering is performed by one or more bandpass filters.

8. (Original): The method of Claim 7, wherein the one or more bandpass filters comprises at least one of a low, medium, or high pass filter.



9. (Original): The method of Claim 6, further comprising:  
generating a focusing signal based on the detected average power; and  
focusing the scanning microscope based on the generated focusing signal.
10. (Original): The method of Claim 9, wherein focusing comprises automatically focusing.
11. (Original): The method of Claim 6, wherein the scanning microscope is a confocal microscope.
12. (Original): An apparatus for indicating real time focus in a scanning microscope, the apparatus comprising:  
a detector for detecting an electrical signal from the scanning microscope;  
one or more bandpass filters for filtering the detected electrical signal, wherein the one or more bandpass filters are tuned to a desired range of frequencies; and  
a focusing device for generating a focusing signal based on the filtered electrical signal and focusing the scanning microscope based on the generated focusing signal.
13. (Original): The apparatus of Claim 12, wherein the focusing device automatically performs generating and focusing.
14. (New): A method for indicating real time focus in a scanning microscope, a method comprising:  
detecting an electrical signal from the scanning microscope;  
filtering the detected electrical signal according to a desired range of frequencies;  
generating a focusing signal based on the filtered electrical signal; and  
focusing the scanning microscope based on the generated focusing signal.
15. (New): The method of Claim 14, wherein generating and focusing are automatically performed.



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